Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	135	(timing) and (criticality) and (model) and (probabilit$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/17 13:13
L2	81	(timing) and (criticality) and (model) and (probabilit$4) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/17 13:14
L3	2	(timing) and (criticality) and (model) and (probabilit$4) and (circuit) and (boundary adj timing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/17 13:14
L4	5	(timing adj criticality) and (model) and (probabilit$4) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/17 13:20
L5	4	(timing adj criticality) and (delay adj model) and (probabilit$4) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/17 13:23
L6	0	(timing adj criticality) and (boundary adj condition$2) and (delay adj model) and (probabilit$4) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/17 13:24
L7	0	(timing adj criticality) and (boundary near condition$2) and (delay adj model) and (probabilit$4) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/17 13:24
L8	1	(timing adj criticality) and (boundary adj (timing adj condition$2)) and (delay adj model) and (probabilit$4) and (circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/17 13:25
S1	1401	716/6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/17 13:11
S2	2275	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:15

S3	1759	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:15
S4	2	(716/6).ccls. and (probabilistic adj (criticality adj prediction))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:17
S5	0	(716/4).ccls. and (probabilistic adj (criticality adj prediction))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:16
S6	0	(716/5).ccls. and (probabilistic adj (criticality adj prediction))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:16
S7	2	("716"/$).ccls. and (probabilistic adj (criticality adj prediction))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:17
S8	3	(probabilistic adj (criticality adj prediction))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:17
S9	1	(716/6).ccls. and (timing adj criticality) and (circuit) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:37
S10	0	(716/4).ccls. and (timing adj criticality) and (circuit) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:37
S11	0	(716/5).ccls. and (timing adj criticality) and (circuit) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:37
S12	1	("716"/$).ccls. and (timing adj criticality) and (circuit) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:37

S13		1	(timing adj criticality) and (circuit) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:38
S14		1	((timing adj criticality) and (circuit) and (parameter$5 adj (delay adj model))).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:41
S15		1	("716"/$).ccls. and (circuit) and (criticality) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:49
S16		2	(circuit) and (criticality) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:46
S17		1	((circuit) and (criticality) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model))).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:46
S18		0	("716"/$).ccls. and (circuit) and (critical adj probability) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:50
S19		1	("716"/$).ccls. and (circuit) and (criticality adj probability) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:50
S20		1	(circuit) and (criticality adj probability) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:50
S21		1	((circuit) and (criticality adj probability) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model))).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:52
S22		1	("716"/$).ccls. and ((circuit) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:53

S23	2	((circuit) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:53
S24	2	((circuit) and (timing adj graph) and (statistical adj timing) and (parameter$5 adj (delay adj model))).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:54
S25	2	("716"/$).ccls. and ((circuit) and (timing adj graph) and (statistical adj timing) and (node$2 and edge$2) and (arrival adj tightness))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:56
S26	3	((circuit) and (timing adj graph) and (statistical adj timing) and (node$2 and edge$2) and (arrival adj tightness))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:56
S27	1	((circuit) and (timing adj graph) and (statistical adj timing) and (node$2 and edge$2) and (arrival adj tightness)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/14 10:56

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☐   1. **Gate sizing using a statistical delay model**
   Jacobs, E.T.A.F.; Berkelaar, M.R.C.M.;
   Design, Automation and Test in Europe Conference and Exhibition 2000. Proc
   27-30 March 2000 Page(s):283 - 290
   Digital Object Identifier 10.1109/DATE.2000.840285

   AbstractPlus | Full Text: PDF(112 KB)   **IEEE CNF**

☐   2. **Statistical delay calculation with vector synthesis model**
   Fujita, T.; Onodera, H.;
   Circuits and Systems, 2000. Proceedings. ISCAS 2000 Geneva. The 2000 IEE
   Symposium on
   Volume 5, 28-31 May 2000 Page(s):473 - 476 vol.5
   Digital Object Identifier 10.1109/ISCAS.2000.857474

   AbstractPlus | Full Text: PDF(284 KB)   **IEEE CNF**

☐   3. **On the guaranteed failing and working frequencies in path delay fault ana**
   Peng, Q.; Agrawal, V.D.; Savir, J.;
   Instrumentation and Measurement Technology Conference, 1999. IMTC/99. Pı
   16th IEEE
   Volume 3, 24-26 May 1999 Page(s):1794 - 1799 vol.3
   Digital Object Identifier 10.1109/IMTC.1999.776130

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┌   1. **Achieving dependability in mission-critical operating systems through ac large-scale functional integration**
Wedde, H.F.; Lind, J.; Eiss, A.;
Parallel and Distributed Systems, 1994. International Conference on
19-21 Dec. 1994 Page(s):655 - 660
Digital Object Identifier 10.1109/ICPADS.1994.590420

AbstractPlus | Full Text: PDF(528 KB)   **IEEE CNF**

┌   2. **Real-time aspects in the development of function block oriented engineei systems**
Prayati, A.; Koubias, S.; Papadopoulos, G.;
Factory Communication Systems, 2002. 4th IEEE International Workshop on
2002 Page(s):157 - 164
Digital Object Identifier 10.1109/WFCS.2002.1159713

AbstractPlus | Full Text: PDF(661 KB)   **IEEE CNF**

┌   3. **A methodology for the development of distributed real-time control appliι focus on task allocation in heterogeneous systems**
Prayati, A.; Koulamas, C.; Koubias, S.; Papadopoulos, G.;
Industrial Electronics, IEEE Transactions on
Volume 51, Issue 6, Dec. 2004 Page(s):1194 - 1207
Digital Object Identifier 10.1109/TIE.2004.837868

AbstractPlus | References | Full Text: PDF(1072 KB)   **IEEE JNL**

┌   4. **Timing minimization by statistical timing hMetis-based partitioning**
Ababei, C.; Bazargan, K.;
VLSI Design, 2003. Proceedings. 16th International Conference on
4-8 Jan. 2003 Page(s):58 - 63
Digital Object Identifier 10.1109/ICVD.2003.1183115

AbstractPlus | Full Text: PDF(326 KB)   **IEEE CNF**

┌   5. **Scheduling algorithms for downlink services in wireless networks: a Marι process approach**
Massey, W.A.; Ramakrisluian, K.G.; Aravamudan, M.; Pai, G.;
Global Telecommunications Conference, 2004. GLOBECOM '04. IEEE
Volume 6, 29 Nov.-3 Dec. 2004 Page(s):4038 - 4042 Vol.6
Digital Object Identifier 10.1109/GLOCOM.2004.1379125

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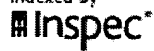| IEEE JNL | IEEE Journal or Magazine |
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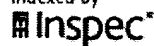|	
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Tzitzirachou, K.D.; Capsalis, C.N.;
Applied Electromagnetism, 2000. Proceedings of the Second International Sym Black Sea Region on
27-29 June 2000 Page(s):25
Digital Object Identifier 10.1109/AEM.2000.943189

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☐   2. **A Gibbs sampling approach to maximum a posteriori time delay and amp**
Michalopoulou, Z.-H.; Picarelli, M.;
Acoustics, Speech, and Signal Processing, 2002. Proceedings. (ICASSP '02). International Conference on
Volume 3, 13-17 May 2002 Page(s):III-3001 - III-3004 vol.3
Digital Object Identifier 10.1109/ICASSP.2002.1005318

AbstractPlus | Full Text: PDF(412 KB)   **IEEE CNF**

☐   3. **Analysis of queuing behavior of automatic ESM systems**
El-Ayadi, M.H.; El-Barbary, K.; Abou-Bakr, H.E.;
Aerospace and Electronic Systems, IEEE Transactions on
Volume 37, Issue 3, July 2001 Page(s):1010 - 1021
Digital Object Identifier 10.1109/7.953253

AbstractPlus | Full Text: PDF(1048 KB)   **IEEE JNL**

☐   4. **Optimistic fossil collection for time warp simulation**
Young, C.H.; Wilsey, P.A.;
System Sciences, 1996., Proceedings of the Twenty-Ninth Hawaii Internationa
Volume 1, 3-6 Jan. 1996 Page(s):364 - 372 vol.1
Digital Object Identifier 10.1109/HICSS.1996.495483

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☐   5. **Simple general formula for PDF of angle of arrival in large cell operationa**
Piechocki, R.J.; Tsoulos, G.V.; McGeehan, J.P.;
Electronics Letters
Volume 34, Issue 18, 3 Sept. 1998 Page(s):1784 - 1785

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